

FA series probe bench is a kind of measuring equipment specially designed for failure analysis laboratory. It has optical characteristic, laser characteristic, stable equipment structure, excellent system performance, ergonomic design, convenient operation, support multi-function upgrade, and rich and complete product functions.

## Basic Information

<b>Product number</b>	FA8	<b>working environment</b>	Open type
<b>electricity demand</b>	220VC,50~60Hz	<b>Control method</b>	Manual Probe Station
<b>Product Size</b>	960mm long *850mm wide *1500mm high	<b>equipment weight</b>	About 260 kg

## Application direction

Chip Failure Analysis AT room temperature and high and low temperature rf device Failure analysis MATERIAL/device IV/CV characteristic test and Failure analysis Chip internal circuit/electrode /PAD test IC/ panel internal circuit modification/layer removal.

## Technical characteristics

### Product Feature

- Large handle drive, no clearance movement.
- Ergonomic design, convenient and comfortable to operate.
- Multi-band laser application, fast switching and accurate cutting.
- Compatible with high power metallographic microscope for fine adjustment and movement.
- No backtrip difference design, accurate positioning.
- The air cooling structure is compact and requires no maintenance.
- High precision system, laser machining accuracy up to 1\*1um.
- Leading internal anti - shock system device, more stable operation.

## 8) H Series Integrated Manual Probe Station